

L Number	Hits	Search Text	DB	Time stamp
1	204	2T2C	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/13 16:23
3	1972	ferroelectric adj random adj access adj memory	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/13 16:23
5	4835	ferroelectric adj capacitor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/13 16:24
6	65	2T2C and (ferroelectric adj random adj access adj memory)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/13 16:24
7	893	(ferroelectric adj random adj access adj memory) and (ferroelectric adj capacitor)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/13 16:24
8	170	2T2C and (ferroelectric adj capacitor)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/13 16:24
9	53	2T2C and (ferroelectric adj random adj access adj memory) and (ferroelectric adj capacitor)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/13 16:24
10	20	(2T2C and (ferroelectric adj random adj access adj memory) and (ferroelectric adj capacitor)) and test	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/13 16:24
11	44	2T2C and 365/149	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/13 16:25
12	11	(ferroelectric adj random adj access adj memory) and (2T2C and 365/149)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/13 16:25
13	17	2T2C and 365/201	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/13 16:25
14	10	(ferroelectric adj random adj access adj memory) and (2T2C and 365/201)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/13 16:25
15	9	2T2C and 365/189.07	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/13 16:26
16	11	(ferroelectric adj capacitor) and ((ferroelectric adj random adj access adj memory) and (2T2C and 365/149))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/13 16:26

17	10	(ferroelectric adj capacitor) and ((ferroelectric adj random adj access adj memory) and (2T2C and 365/201))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/13 16:26
18	8	(ferroelectric adj capacitor) and (2T2C and 365/189.07)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/13 16:26
-	3292	ferroelectric and DRAM	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/29 13:55
-	530	(ferroelectric and DRAM) and test	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/29 13:55
-	402	((ferroelectric and DRAM) and test) and capacitor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/29 13:56
-	107	((ferroelectric and DRAM) and test) and capacitor) and differential	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/29 14:06
-	214	test and (365/149.ccls.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/29 14:06
-	135	(test and (365/149.ccls.)) and (sense adj amplifier)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/29 14:06
-	23	((test and (365/149.ccls.)) and (sense adj amplifier)) and ferroelectric	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/29 14:10
-	62	((test and (365/149.ccls.)) and (sense adj amplifier)) and differential	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/29 14:10